# **BEAM DYNAMICS WITH ELECTRON COOLING**

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#### Abstract

Electron cooling experiments have been carried out at HIMAC in order to develop new technologies in heavy-ion therapy and related researches. The cool-stacking method, in particular, has been studied to increase the intensity of heavy-ions. The maximum stack intensity was 2 mA, above which a fast ion losses occurred simulatneously with the vertical coherent oscillations. The instability depends on the working point, the stacked ion-density and the electron-beam density. The instability was suppressed by reducing the peak ion-density with RF-knockout heating.

# **INTRODUCTION**

The electron cooling experiments at HIMAC<sup>1</sup> synchrotron have been carried out since 2000 in order to develop new technologies in heavy-ion therapy and related fields. One of the objectives of the HIMAC cooler is to increase the beam intensity of heavier ions such as Fe, for risk estimations under low-dose exposure in space [1]. For the purpose, the cool-stacking method has been studied at the HIMAC synchrotron, because the electron-cooling method can provide high-intensity beams by its strong phase-space compression. The electron cooling experiments were carried out with coasting beams of Ar<sup>18+</sup> ions at injection energy of 6 MeV/u.

The HIMAC synchrotron adopts the multi-turn beam injection using the horizontal space. The full emittance of a beam after one batch injection is around 260  $\pi$ mm-mrad in horizontal and 10  $\pi$ mm-mrad in vertical spaces, respectively. The intensity and momentum spread of a beam are typically  $(0.3\sim0.7)\times10^9$  particle per pulse (ppp) and  $\pm0.1\%$ , respectively.

The stack intensity of ion beam at K'th injection is given by

$$N_K = N_0 \frac{1 - \exp(-KT_0/\tau)}{1 - \exp(-T_0/\tau)},$$
(1)

where  $N_0$  is the number of ions in one-batch injection,  $T_0$  the injection-repetition period and  $\tau$  the ion-beam lifetime. Our experimental results showed that the lifetime was decreased at higher ion-beam intensity (N), depending on electron-beam current ( $I_e$ ) and its magnetic expansion factor (R). The lifetime reduction was small at higher electron beam density, as described in Sec. 2.

The maximum stacked intensity with  $N_0 = 0.03 \times 10^9$ and  $T_0 = 3.3$  s was  $(0.3 \sim 0.4) \times 10^9$  ions [2]. However, the intensity higher than that was restricted by ion-beam instability [3]. The ion-beam instability occurred when the



Figure 1: Transverse FWHM beam-sizes during stackdecay. The curve corresponds to Eq. (2).

ion- and electron-beam density was high [4]. The instability correlated with the burst of coherent vertical oscillations, as descibed in Sec. 3. Such instability was observed at CELSIUS, Indiana cooler, SIS and COSY [5]. The instability at the HIMAC synchrotron essentially depends on the working point and had a maximum increment at a coupling resonance  $Q_x - Q_y = 1$ . The instability was related with so called electron heating [6, 7, 8]. The instability could be suppressed by RF-knockout heating, which is also described in Sec. 3.

## **COOL STACKING**

# Transverse Beam Density

The profile of a coasting ion-beam was measured during cooling with R=3.3 and  $I_e$ =50 mA, which corresponds to electron-current density of 1.55 mA. Ion-beam intensity corresponds to  $0.5 \times 10^9$  ions and was very slowly decreased with the lifetime of  $5 \sim 6$  s. The transverse cooling was saturated at the FWHM sizes of (6 mm,6 mm). The peak ion-density, when Gaussian distribution was assumed, corresponds to

$$\frac{1}{2\pi} \frac{N}{\sigma_x \sigma_y} = 0.16 \times 10^9 \text{ ions/cm}^2, \qquad (2)$$

where  $\sigma_{x,y}$  are the horizontal and the vertical rms sizes, respectively. The cooling time corresponds to around  $2 \sim 3$  s.

Ion-intensity was increased by cool-stacking injection. Ion-intensity of up to  $\sim 1.5 \times 10^9$  ppp was stacked with  $T_0=1.65$  s. The beam profiles were measured during the stack-decay after stopping ion-beam injection. The FWHM beam size was proportional to the square root of beam intensity throughout the stack-decay, and was in good agree-

<sup>&</sup>lt;sup>1</sup>Heavy Ion Medical Accelerator in Chiba



Figure 2: Lifetime vs ion intensity for various expansion factors (R). Electron current ( $I_e$ ) is 100 mA.

ment with Eq.(2) as shown in Fig. 1. The density limit was constant at 2.8 < R < 3.3 within the mesurement accuracy.

### Lifetime Reduction

The intensity-dependent lifetime of ion-beam was measured by analyzing the beam-intensity waveform during stack-decay. Figure 2 shows the ion-beam lifetime at  $I_e$ =100 mA and  $T_0$ =3.3 s, as a function of ion-intensity. The lifetime was 8 s at a low-intensity of ~  $5 \times 10^7$  ppp, and was decreased to 3 ~ 5 s at a high intensity of ~  $10^9$  ppp.

Fig. 2 shows that the lifetime became higher when R is low. The lifetime was also measured with different  $I_e$ , as shown in Fig. 3. Here, the COD was fairly corrected and the injection repetition ( $T_0$ ) was reduced from 3.3 s to 1.65 s, so that the ion-intensity became higher comparing with Fig. 2. Both of Figs. 2 and 3 shows that the ion-beam lifetime was high when electron dencity ( $\propto I_e/R$ ) was high.

#### Maximum Stacked Intensity

The stacked ion-beam intensity was increased by optimizing  $I_e$ , R,  $T_0$  [9],  $N_0$ , and the bump-orbit matching. As a result, the maximum stacked intensity of  $2.1 \times 10^9$  ppp was obtained with  $T_0=1.0$  s,  $I_e=130$  mA, R=1.7, as Fig. 4. Here, a transverse RF of 8 V was applied at 225 kHz in order to suppress ion-beam instability, which is described in the next section.

#### INSTABILITY

### Transverse Instability

Ion instability occurred when the densities of ions and electrons were high [3]. Figure 5 shows the typical waveform of ion intensity and vertical coherent oscillation, when the instability occurred. Here,  $I_e$ =150 mA, R=3.3, and working point was (3.69,2.89). The ion beam was suddenly lost during instability at around 5.5 s, which was correlated with the bursts of vertical coherent oscillations.



Figure 3: Lifetime vs ion intensity for various electron currents  $(I_e)$ . Magnetic expansion factor (R) is 3.3.



Figure 4: Stack intensity of  $2.5 \times 10^9$  ppp was obtained.

The frequency of the oscillations agrees with the vertical betatron-sideband frequency.

The instability essentially depends on working point. The working points were surveyed along a line between (3.69,2.89) and (3.72,3.13). It was found that the beam was unstable near to the coupling resonances,  $Q_x + Q_y = 7$  and  $Q_x - Q_y = 1$ . Further, beam-profile measurements showed that the direction of the amplitude growth caused by the instability was slightly inclined in the transverse plane [4]. The bandwidth of the instability was wider at the difference resonance than the sum resonance. These results are consistent with the simulation including the coherent interaction between electron- and ion-beam via space-charge fields [4].

Though the instability occurred at high ion-density, it is possible to to suppress the instability by decreasing the peak ion-density. The RF-knockout(RF-KO) was applied near the frequency corresponding to the vertical betatronsideband frequency in order to decrease the peak density of the ion-beam. With the RF-KO, the coherent oscillation was suppressed and the stacked ion-intensity was improved as shown in Fig. 6



Figure 5: Waveform of ion intensity and vertical differenpickup signal when instability was developed.

#### Electron Beam Instability

Secondary ions trapped in the electron beam may cause electron beam instability. The partially neutralized electron beam is itself unstable at a threshold current denof [10, 11]

$$j_{\rm th} = \frac{k' \pi \epsilon_0}{2} \frac{\beta^2 c^2 B_{sol}}{L_e} \tag{3}$$

without any ion stack interaction, where  $B_{sol}$  is the strength the solenoid for electron focusing,  $L_e$  the length of the

partially neutralized electron beam, and k' is the numericoefficient depending on the structure of ion trap. The threshold current density of HIMAC cooler was estimated

to be 9 mA/cm<sup>2</sup>.

The maximal electron current, which was available for electron cooling at the HIMAC cooler, was measured a stack intensity of  $2.5 \times 10^9$  ppp. The stacked ion beam was stable at  $I_e$  less than 130 mA at the electron beam diameter of 4.6 cm, which corresponds to the elected ensity of 8 mA/cm<sup>2</sup>.

#### **SUMMARY**

Electron-cool stacking experiments have been done at HIMAC synchrotron. There was a limit of transverse coolat ion peak-density of  $0.16 \times 10^9$  ions/cm<sup>2</sup>. By analyzthe stack-decay, it was found that the ion-beam lifetime reduced at ion intensity higher than  $\sim 0.5 \times 10^9$  ppp. lifetime reduction became smaller when the density of electron beam was higher. There was a certain threshof ion-density, above which a coherent instability oc-

curred. The instability was suppressed by reducing the



Figure 6: Transverse instability (upper) was suppressed by RF-KO heating (lower).

### REFERENCES

- [1] K. Noda et al., NIM A441(2000)159.
- [2] K. Noda et al., Proc. of the workshop on Ion Beam Cooling Toward the Crystalline Beam, Kyoto, Japan(2001),pp.129.
- [3] K. Noda et al., EPAC'02, Paris, June 2002, pp.1380.
- [4] T. Uesugi et al., EPAC'04, Lucerne, Jul 2004.
- [5] See references listed in Ref. [4]
- [6] V. V. Parkhomchuk and V. B. Reva, Journal of Experimental and Theoretical Physics, v.91, N5 (2000), 975.
- [7] P. R. Zenevich and A. E. Bolshakov, NIM A441 (2000), 36.
- [8] A. Burov, NIM A441 (2000), 23.
- [9] K. Noda et al., EPAC'04, Lucerne, Jul 2004.
- [10] J. Bosser et al., NIM A391 (1997), 110.
- [11] A. V. Burov et al., Preprint BINP 89-116, CERN PS 93-09, 1993.